

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	49	US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:14
S2	3633	((optical near3 fiber\$1) and defect\$7) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:01
S3	19	((((optical near3 fiber\$1) and defect\$7) and filter\$1) and Gabor\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:14
S4	488	machine near3 vision near3 inspection\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:25
S5	2	((machine near3 vision near3 inspection\$1) and filters) and gabor	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:13

S6	122	(machine near3 vision near3 inspection\$1) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:58
S7	48	((machine near3 vision near3 inspection\$1) and filters) and fiber\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:30
S8	8	(machine near3 vision near3 inspection\$1) and (bandpass near3 filters)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:36
S9	2	((optical\$4 near3 fiber\$1) near4 defect\$8) same (bandpass near3 filters)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:43
S10	363	(optical\$3 near3 fiber\$1) near3 inspection	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:59
S11	43	((optical\$3 near3 fiber\$1) near3 inspection) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 16:09
S12	5366	gabor	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42
S13	128	gabor near2 filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42

S14	2	(gabor near2 filters) and fiber	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42
S15	193	filters same (fiber\$1 and Defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:45
S16	61	filters same ((optical near3 fiber\$1) and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:50
S17	1855	((optical near3 fiber\$1 near3 end\$1) and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:51
S18	350	(((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:54
S19	168	((((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters) and (spots or scratch\$2 or (cladd\$4 naer3 boundar\$4 near3 defect\$1) or crack\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:55
S20	116	((((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters) and (spots or scratch\$2 or (cladd\$4 near3 boundar\$4 near3 defect\$1) or crack\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:19
S21	6227	382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:16

S22	2149	382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:29
S23	691	(382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:30
S24	352	(382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:14
S25	49	US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:19

S26	6	(US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:15
-----	---	----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------	--------------------------------------------------------------	----	-----	---------------------

S27	43	(US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) not ((US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) and filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:19
-----	----	-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------	--------------------------------------------------------------	----	-----	---------------------

S28	60	(digital near3 imag\$3) same (filters and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:24
S29	0	(digital near3 imag\$3) same filters0 and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:25
S30	244	((digital near3 imag\$3) same filters) and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:50
S31	6	((digital near3 imag\$3) same (spatial near3 filters)) and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:30
S32	13	spatial near3 bandpass near3 filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:05
S33	923	imag\$3 and (spatial near3 filters) and (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:08
S34	426	(imag\$3 same (spatial near3 filters)) and (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:08
S35	68	(imag\$3 same (spatial near3 filters)) same (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:32

S36	72	(imag\$3 same (spatial near3 filters)) same (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4 or flaw\$)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:32
S37	5370	GABOR	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:31
S38	213	GABOR NEAR3 FILTER\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:31
S39	115	(GABOR NEAR3 FILTER\$1) and (defect\$1 or flaw\$1 or error\$1 or crack\$1 or scratch\$3 or spot\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:32
S40	118	image\$1 same (Fourier near3 transform\$3) same ((power near4 two) or (2x2 or 4x4 or 16x16))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/30 13:26
S41	5	interpolat\$6 same (gabor near3 filter\$)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/30 13:29
S42	2	"6753965".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:16
S43	6649	382/100,141;348/86,88,125;700/95,142,143;356/73.1,901,429,430.ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:38

S44	2	"5995212".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:27
S45	388	S43 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:38
S46	8163	382/100,141,142,143,144, 145,146,147,148,149;348/86, 88,125;700/95,142, 143;356/73.1,901,429,430. ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:02
S47	483	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:36
S48	80	S47 and (("max." maximum max highest most) near6 pixel\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:39
S49	30	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 (bandpass near3 filter\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:48
S50	23	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 (spatial near3 filter\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:48
S51	503	S46 and ((defect\$3 inspection\$4 deform\$6) same (thread\$1 fiber\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03

S52	48	S51 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:51
S53	48	S51 and ((bank set multiple plural\$4 several two three four five six seven group\$1) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:52
S54	2971	356/73.1,239.2,901,429,430. ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S55	183	S54 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S56	22	S55 and ((defect\$3 inspection\$4 deform\$6) same (thread\$1 fiber\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S57	6	"6636298".pn.",6408429".pn. ",6748104".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:08
S58	52457	((bandpass Gabor\$1 spatial\$3) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:37
S59	2460	((bandpass Gabor\$1 spatial\$3) near4 filter\$1) same (thread\$1 fiber\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:37

S60	450	S59 and (inspect\$ defect\$5)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:38
-----	-----	-------------------------------	--------------------------------------------------------------	----	-----	---------------------


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

☐ Search Results[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((inspect* <or> defect*) <paragraph>((bank <or> set*, multiple*, plural*, several..."
 Your search matched **42** of **1164322** documents.
 A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

☐ e-mail[» View Session History](#)[» New Search](#)[» Key](#)

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Modify Search

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

- | Select | Article Information |
|--------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <input type="checkbox"/> | 1. Fiber-optic multiple-wavelength filter based on one-dimensional photonic bandg: with defects
Del Villar, I.; Matias, I.R.; Arregui, F.J.;
Lightwave Technology, Journal of
Volume 22, Issue 6, June 2004 Page(s):1615 - 1621
AbstractPlus References Full Text: PDF(400 KB) IEEE JNL |
| <input type="checkbox"/> | 2. Control of bandstop response of Hi-Lo microstrip low-pass filter using slot in grc
Abdel-Rahman, A.B.; Verma, A.K.; Boutejdar, A.; Omar, A.S.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 52, Issue 3, March 2004 Page(s):1008 - 1013
AbstractPlus References Full Text: PDF(304 KB) IEEE JNL |
| <input type="checkbox"/> | 3. A neural fuzzy network approach to Radar pulse compression
Fun-Bin Duh; Chia-Feng Juang; Chin-Teng Lin;
Geoscience and Remote Sensing Letters, IEEE
Volume 1, Issue 1, Jan. 2004 Page(s):15 - 20
AbstractPlus References Full Text: PDF(280 KB) IEEE JNL |
| <input type="checkbox"/> | 4. Multiple defect characterization in finite-size waveguiding photonic bandgap stru
Giorgio, A.; Pasqua, D.; Perri, A.G.;
Quantum Electronics, IEEE Journal of
Volume 39, Issue 12, Dec. 2003 Page(s):1537 - 1547
AbstractPlus References Full Text: PDF(1080 KB) IEEE JNL |
| <input type="checkbox"/> | 5. Automated flaw detection in aluminum castings based on the tracking of potenti: radioscopic image sequence
Mery, D.; Filbert, D.;
Robotics and Automation, IEEE Transactions on
Volume 18, Issue 6, Dec. 2002 Page(s):890 - 901
AbstractPlus References Full Text: PDF(1224 KB) IEEE JNL |
| <input type="checkbox"/> | 6. Wavelet-based processing of ECT images for inspection of printed circuit board
Taniguchi, T.; Kacprzak, D.; Yamada, S.; Iwahara, M.;
Magnetism, IEEE Transactions on
Volume 37, Issue 4, July 2001 Page(s):2790 - 2793
AbstractPlus References Full Text: PDF(160 KB) IEEE JNL |

- ☐ **7. Wavelet packet-based EMI signal processing and source identification**
Antonini, G.; Orlandi, A.;
Electromagnetic Compatibility, IEEE Transactions on
Volume 43, Issue 2, May 2001 Page(s):140 - 148
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(256 KB) IEEE JNL

- ☐ **8. Analysis, design, and implementation of two-channel linear-phase filter banks: a**
Pinchon, D.; Siohan, P.;
Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Pro
Transactions on]
Volume 46, Issue 7, July 1998 Page(s):1814 - 1826
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(532 KB) IEEE JNL

- ☐ **9. Microring resonator channel dropping filters**
Little, B.E.; Chu, S.T.; Haus, H.A.; Foresi, J.; Laine, J.-P.;
Lightwave Technology, Journal of
Volume 15, Issue 6, June 1997 Page(s):998 - 1005
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(284 KB) IEEE JNL

- ☐ **10. Optimal testing of VLSI analog circuits**
Chieh-Yuan Chao; Hung-Jen Lin; Miller, L.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 16, Issue 1, Jan. 1997 Page(s):58 - 77
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(536 KB) IEEE JNL

- ☐ **11. Sampling and Reconstruction of NTSC Video Signals at Twice the Color Subcarr**
Ouellet, J.-Y.; Dubois, E.;
Communications, IEEE Transactions on [legacy, pre - 1988]
Volume 29, Issue 12, Dec 1981 Page(s):1823 - 1832
[AbstractPlus](#) | Full Text: [PDF](#)(872 KB) IEEE JNL

- ☐ **12. Application of parallel processing techniques to eddy-current NDT instrumentati**
Bahramparvar, M.R.; Gray, J.O.;
Control Theory and Applications, IEE Proceedings-
Volume 137, Issue 4, Jul 1990 Page(s):211 - 224
[AbstractPlus](#) | Full Text: [PDF](#)(900 KB) IEE JNL

- ☐ **13. Fast object localization using multi-scale image relevance function**
Palenichka, R.M.; Missaoui, R.; Zaremba, M.B.;
Pattern Recognition, 2004. ICPR 2004. Proceedings of the 17th International Conferen
Volume 3, 23-26 Aug. 2004 Page(s):227 - 230 Vol.3
[AbstractPlus](#) | Full Text: [PDF](#)(407 KB) IEEE CNF

- ☐ **14. Texture inspection with self-adaptive convolution filters**
Dewaele, P.; Van Gool, L.; Wambacq, A.; Oosterlinck, A.;
Pattern Recognition, 1988., 9th International Conference on
14-17 Nov. 1988 Page(s):56 - 60 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(616 KB) IEEE CNF

- ☐ **15. A well-shielded EMAT for on-line ultrasonic monitoring of GMA welding**
Clark, A.V.; Schaps, S.R.; Fortunko, C.M.;
Ultrasonics Symposium, 1991. Proceedings., IEEE 1991
8-11 Dec. 1991 Page(s):337 - 340 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(272 KB) IEEE CNF

- ☐ **16. 3-D signal processing in a computer vision system [hardwood logs inspection]**
Zhu, D.; Connors, R.W.; Araman, P.;
Systems Engineering, 1991., IEEE International Conference on
1-3 Aug. 1991 Page(s):457 - 460
[AbstractPlus](#) | Full Text: [PDF\(360 KB\)](#) IEEE CNF

- ☐ **17. Segmentation of defects in textile fabric**
Neubauer, C.;
Pattern Recognition, 1992 . Vol.1. Conference A: Computer Vision and Applications, PI
IAPR International Conference on
30 Aug.-3 Sept. 1992 Page(s):688 - 691
[AbstractPlus](#) | Full Text: [PDF\(500 KB\)](#) IEEE CNF

- ☐ **18. Filter tuning by iterative defect correction (IDeC)**
Wai, N.S.;
Circuits and Systems, 1993., ISCAS '93, 1993 IEEE International Symposium on
3-6 May 1993 Page(s):2257 - 2259 vol.4
[AbstractPlus](#) | Full Text: [PDF\(192 KB\)](#) IEEE CNF

- ☐ **19. 3-D multiphoton laser scanning confocal microscopy as a probe for subsurface polymers**
Bhawalkar, J.D.; Swiatkiewicz, J.J.; He, G.S.; Prasad, P.N.; Pan, S.J.; Samarabandu, J.;
Cheng, P.C.;
Lasers and Electro-Optics, 1996. CLEO '96., Summaries of papers presented at the Conference
2-7 June 1996 Page(s):19 - 20
[AbstractPlus](#) | Full Text: [PDF\(220 KB\)](#) IEEE CNF

- ☐ **20. Proceedings of 3rd IEEE International Conference on Image Processing**
Image Processing, 1996. Proceedings., International Conference on
Volume 1, 16-19 Sept. 1996
[AbstractPlus](#) | Full Text: [PDF\(2268 KB\)](#) IEEE CNF

- ☐ **21. Texture defect detection using the adaptive two-dimensional lattice filter**
Meylani, R.; Ertuzun, A.; Ercil, A.;
Image Processing, 1996. Proceedings., International Conference on
Volume 3, 16-19 Sept. 1996 Page(s):165 - 168 vol.3
[AbstractPlus](#) | Full Text: [PDF\(552 KB\)](#) IEEE CNF

- ☐ **22. Perception of an underwater structure for inspection and guidance purpose**
Tascini, G.; Zingaretti, P.; Conte, G.; Zanolli, S.M.;
Advanced Mobile Robot, 1996., Proceedings of the First Euromicro Workshop on
9-11 Oct. 1996 Page(s):24 - 28
[AbstractPlus](#) | Full Text: [PDF\(672 KB\)](#) IEEE CNF

- ☐ **23. Low-cost and minimal conditioning interface for a PbSe photoconductor array [for defect detection]**
Chavez, J.A.; Ortega, J.A.; Perez, M.A.; Garcia, M.J.;
Instrumentation and Measurement Technology Conference, 1996. IMTC-96. Conference on
'Quality Measurements: The Indispensable Bridge between Theory and Reality', IEEE
Volume 1, 1996 Page(s):549 - 553 vol.1
[AbstractPlus](#) | Full Text: [PDF\(540 KB\)](#) IEEE CNF

- ☐ **24. Processing issues in the automated inspection of power insulators**
Wei Chen; Acton, S.T.;
Image Analysis and Interpretation, 1996., Proceedings of the IEEE Southwest Symposium
8-9 April 1996 Page(s):24 - 29
[AbstractPlus](#) | Full Text: [PDF\(616 KB\)](#) IEEE CNF

**25. Protein fold recognition from secondary structure assignments**

Russell, R.B.; Copley, R.R.; Barton, G.J.;

System Sciences, 1995. Vol. V. Proceedings of the Twenty-Eighth Hawaii International
Volume 5, 3-6 Jan. 1995 Page(s):302 - 311 vol.5[AbstractPlus](#) | Full Text: [PDF\(752 KB\)](#) [IEEE CNF](#)

Indexed by

 Inspec[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE –


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)
[BROWSE](#)
[SEARCH](#)
[IEEE XPLORE GUIDE](#)

Results for "(((inspect* <or> defect*) <paragraph>((bank <or> set*, multiple*, plural*, several..."

e-mail

Your search matched 42 of 1164322 documents.

A maximum of 42 results are displayed, 25 to a page, sorted by Relevance in Descending order.

[» View Session History](#)
[» New Search](#)

Modify Search

» Key

IEEE JNL IEEE Journal or Magazine

☐ Check to search only within this results set

IEE JNL IEE Journal or Magazine

Display Format: ☒ Citation ☐ Citation & Abstract

IEEE CNF IEEE Conference Proceeding

Select Article Information

IEE CNF IEE Conference Proceeding

☐ 26. A control method of active power filter where system voltage contains negative-
component or zero-phase-sequence component

 Komatsu, Y.; Kawabata, T.;
Power Electronics and Drive Systems, 1995., Proceedings of 1995 International Confe
21-24 Feb. 1995 Page(s):583 - 586 vol.2

[AbstractPlus](#) | Full Text: [PDF](#)(132 KB) IEEE CNF

IEEE STD IEEE Standard

☐ 27. Analysis of a delayless subband adaptive filter
Hirayama, N.; Sakai, H.;
Acoustics, Speech, and Signal Processing, 1997. ICASSP-97., 1997 IEEE Internationa
Volume 3, 21-24 April 1997 Page(s):2329 - 2332 vol.3

[AbstractPlus](#) | Full Text: [PDF](#)(328 KB) IEEE CNF

☐ 28. An 0.8 μ m CMOS mixed analog-digital integrated audiometric system
Brigati, S.; Francesconi, F.; Grassi, G.; Lissoni, D.; Malcovati, P.; Nobile, A.; Poletti, M.
Solid-State Circuits Conference, 1998. Digest of Technical Papers. 45th ISSCC 1998 I
5-7 Feb. 1998 Page(s):116 - 117, 423

[AbstractPlus](#) | Full Text: [PDF](#)(524 KB) IEEE CNF

☐ 29. Optimization of regularization of attenuation and scatter corrected ^{99m}Tc cardiac
for defect detection using hybrid images
Narayanan, M.V.; King, M.A.; Leppo, J.; Dahlberg, S.; Pretonus, P.H.; Gifford, H.C.;
Nuclear Science Symposium Conference Record, 2000 IEEE
Volume 2, 15-20 Oct. 2000 Page(s):13/82 - 13/86 vol.2

[AbstractPlus](#) | Full Text: [PDF](#)(448 KB) IEEE CNF

☐ 30. Active infrared nondestructive testing for glue occlusion detection in plastic cap
Legrand, A.-C.; Gorria, P.; Meriaudeau, F.;
Knowledge-Based Intelligent Engineering Systems and Allied Technologies, 2000. Pro
International Conference on
Volume 1, 30 Aug.-1 Sept. 2000 Page(s):381 - 384 vol.1

[AbstractPlus](#) | Full Text: [PDF](#)(296 KB) IEEE CNF

☐ 31. Improvement of the official examinations for the signal quality of the cable TV sy
Taiwan: the modification of the automatic measurement software
Bing-Yuh Lu; Yigh-Pyng Lin; Hai-Han Lu; Hung-Wen Hung; Chin-Yuan Lin; Te-Son Ku;
Instrumentation and Measurement Technology Conference, 2000. IMTC 2000. Procee

IEEE

Volume 1, 1-4 May 2000 Page(s):473 - 477 vol.1

[AbstractPlus](#) | Full Text: [PDF\(648 KB\)](#) IEEE CNF

- ☐ **32. Thermal stability of ZnMgSSe/ZnSe laser heterostructures**
Marko, I.P.; Yablonskii, G.P.; Gurskii, A.L.; Lutsenko, E.V.; Kalisch, H.; Heuken, M.; Winkler, K.;
Compound Semiconductors, 2000 IEEE International Symposium on
2-5 Oct. 2000 Page(s):67 - 71
[AbstractPlus](#) | Full Text: [PDF\(240 KB\)](#) IEEE CNF
- ☐ **33. Integrated spline wavelet and Kalman filter approach for power quality monitoring network**
Dash, P.K.; Sahoo, D.K.; Panigrahi, B.K.; Panda, G.;
Power Electronics and Drive Systems, 2001. Proceedings., 2001 4th IEEE International Conference on
Volume 2, 22-25 Oct. 2001 Page(s):858 - 863 vol.2
[AbstractPlus](#) | Full Text: [PDF\(323 KB\)](#) IEEE CNF
- ☐ **34. Rail corrugation detection by Gabor filtering**
Mandriota, C.; Stella, E.; Nitti, M.; Ancona, N.; Distanto, A.;
Image Processing, 2001. Proceedings. 2001 International Conference on
Volume 2, 7-10 Oct. 2001 Page(s):626 - 628 vol.2
[AbstractPlus](#) | Full Text: [PDF\(216 KB\)](#) IEEE CNF
- ☐ **35. 2-D photonic crystal filters: a channel dropping radiation filter and a peak transmission mode matching features**
Hattori, H.; Jugessur, A.S.; Viktorovitch, P.; De La Rue, R.M.;
Lasers and Electro-Optics Society, 2002. LEOS 2002. The 15th Annual Meeting of the IEEE
Volume 2, 10-14 Nov. 2002 Page(s):673 - 674 vol.2
[AbstractPlus](#) | Full Text: [PDF\(237 KB\)](#) IEEE CNF
- ☐ **36. A tale of two filters-on-line novelty detection**
Crook, P.A.; Marsland, S.; Hayes, G.; Nehmzow, U.;
Robotics and Automation, 2002. Proceedings. ICRA '02. IEEE International Conference on
Volume 4, 11-15 May 2002 Page(s):3894 - 3899 vol.4
[AbstractPlus](#) | Full Text: [PDF\(696 KB\)](#) IEEE CNF
- ☐ **37. Trade off study on different envelope detectors for B-mode imaging**
Schlaikjer, M.; Bagge, J.P.; Sorensen, O.M.; Jensen, J.A.;
Ultrasonics, 2003 IEEE Symposium on
Volume 2, 5-8 Oct. 2003 Page(s):1938 - 1941 Vol.2
[AbstractPlus](#) | Full Text: [PDF\(394 KB\)](#) IEEE CNF
- ☐ **38. Substructuring approach to optimization of matching structures for photonic crystal**
Hershkoviz, O.; Steinberg, B.Z.; Boag, A.;
Electrical and Electronics Engineers in Israel, 2004. Proceedings. 2004 23rd IEEE Conference on
6-7 Sept. 2004 Page(s):247 - 250
[AbstractPlus](#) | Full Text: [PDF\(351 KB\)](#) IEEE CNF
- ☐ **39. Fabric defects automatic detection using Gabor filters**
Yuan Shu; Zheng Tan;
Intelligent Control and Automation, 2004. WCICA 2004. Fifth World Congress on
Volume 4, 15-19 June 2004 Page(s):3378 - 3380 Vol.4
[AbstractPlus](#) | Full Text: [PDF\(359 KB\)](#) IEEE CNF
- ☐ **40. A machine vision system for inspecting bearing-diameter**
Liangyu Lei;

Intelligent Control and Automation, 2004. WCICA 2004. Fifth World Congress on
Volume 5, 15-19 June 2004 Page(s):3904 - 3906 Vol.5

[AbstractPlus](#) | Full Text: [PDF\(328 KB\)](#) IEEE CNF



41. Kalman filter based non-destructive test instrument

Bahramparvar, M.R.; Gray, J.O.;

Kalman Filters: Introduction, Applications and Future Developments, IEE Colloquium on
21 Feb 1989 Page(s):7/1 - 7/3

[AbstractPlus](#) | Full Text: [PDF\(128 KB\)](#) IEE CNF



42. Application of parallel processing techniques in a Kalman filter based NDT instru

Bahramparvar, M.R.; Gray, J.O.;

Recent Advances in Parallel Processing for Control, IEE Colloquium on
7 Jul 1988 Page(s):6/1 - 6/6

[AbstractPlus](#) | Full Text: [PDF\(248 KB\)](#) IEE CNF



Indexed by
 Inspec

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE –